

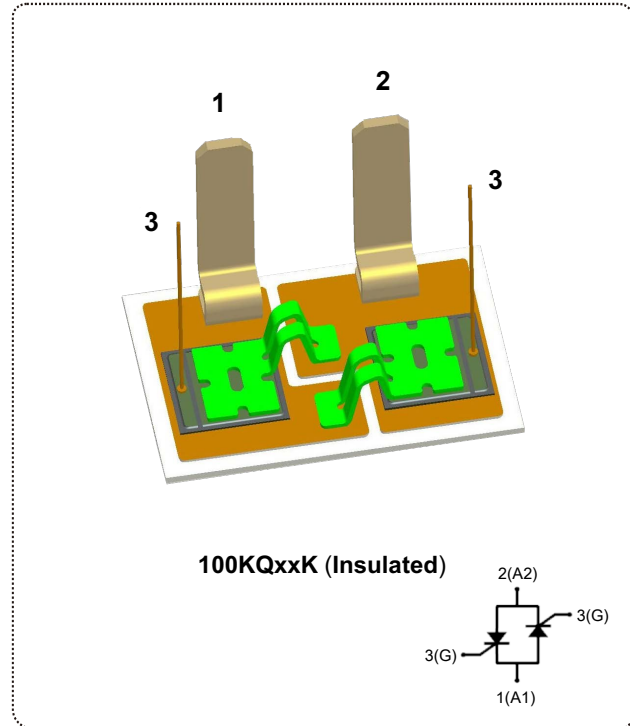
Antiparallel Thyristor Module, 100A (DBC Module, open-frame type) Snubberless

FEATURES

- Glass passivated thyristor chips
- Low thermal resistance with clip bonding
- Low thermal resistance for DBC package
- High commutation capability
- Packages are RoHS compliant

APPLICATIONS

- DC motor control
- Temperature control
- Lighting control
- Soft starters



MAIN FEATURES		
SYMBOL	VALUE	UNIT
$I_{T(RMS)}$	100	A
V_{DRM}/V_{RRM}	1200 to 1600	V
V_{RSM}	1300 to 1700	V
$I_{GT(Q1)}$	max.80	mA

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	SYMBOL	TEST CONDITIONS		VALUE	UNIT
RMS on-state current (full sine wave)	$I_{T(RMS)}$	W1C Sin.180°	$T_c=80^\circ\text{C}$	100	A
			$T_c=100^\circ\text{C}$	70	
Non repetitive surge peak on-state current (full cycle)	I_{TSM}	$F = 50 \text{ Hz}, V_R = 0.6 V_{RRM}, T_j = 25^\circ\text{C}$	$t=10 \text{ ms}$	1200	A
		$F = 50 \text{ Hz}, V_R = 0.6 V_{RRM}, T_j = 125^\circ\text{C}$	$t=10 \text{ ms}$	840	
I^2t Value for fusing	I^2t	$T_j = 25^\circ\text{C}$	$t=10 \text{ ms}$	1000	A ² s
		$T_j = 125^\circ\text{C}$	$t=10 \text{ ms}$	720	
Critical rate of rise of on-state current $I_G = 2xI_{GT}, t_r \leq 100\text{ns}$	di/dt	$V_D = 66.7\% V_{DRM}, t_p = 200\mu\text{s}, I_G = 0.3\text{A}, di_G/dt = 0.3\text{A}/\mu\text{s}$	$T_j=125^\circ\text{C}$	100	A/ μs
Turn-Off Time	t_q		$T_j=125^\circ\text{C}$	8	A
Gate-controlled delay time	t_{gd}	$I_G = 1\text{A}; di_G/dt = 1\text{A}/\mu\text{s}$	$T_j=25^\circ\text{C}$	1	μs
Gate-controlled rise time	t_{gr}	$V_D = 0.67*V_{DRM}$		2	
Storage temperature range	T_{stg}			- 40 to + 150	°C
Operating junction temperature range	T_j			- 40 to + 125	

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SNUBBERLESS and Logic level (3 quadrants)					
SYMBOL	TEST CONDITIONS	QUADRANT		VALUE	Unit
I _{GT} ⁽¹⁾	V _D = 12 V, R _L = 30Ω	I - II - III	MAX.	80	mA
V _{GT}		I - II - III		2	V
V _{GD}	V _D = V _{DRM} , R _L = 3.3KΩ T _j = 125°C	I - II - III	MIN.	0.25	V
I _{GD}		I - II - III	MIN.	3	mA
I _H ⁽²⁾	I _T = 1000 mA	I - II - III	MAX.	120	mA
I _L	I _G = 1.2 I _{GT}	I - II - III	MAX.	300	mA
dV/dt ⁽²⁾	V _D = 66.7% V _{DRM} , gate open, T _j = 125°C		MIN.	1000	V/μs
V _{INS}	Insulation voltage, AC 50 HZ ; R.M.S. ; 1s/60s			3000/2500	V

STATIC CHARACTERISTICS					
SYMBOL	TEST CONDITIONS			VALUE	UNIT
V _{TM} ⁽²⁾	I _{TM} = 100 A, t _p = 380 μs	T _j = 25°C	MAX.	1.35	V
V _{th} ⁽²⁾	Threshold voltage	T _j = 125°C	MAX.	0.8	V
R _d ⁽²⁾	Dynamic resistance	T _j = 125°C	MAX.	10	mΩ
I _{DRM} I _{RSM}	V _D = V _{DRM} V _R = V _{RRM}	T _j = 25°C	MAX.	0.5	mA
		T _j = 125°C		10	mA

Note 1: Minimum I_{GT} is guaranteed at 5% of I_{GT} max.

Note 2: For both polarities of A2 referenced to A1.

THERMAL RESISTANCE					
SYMBOL	TEST CONDITIONS			VALUE	UNIT
R _{th(j-c)}	Junction to DBC (AC)			0.28	°C/W
R _{th(j-s)}	cont.per thyristor			1.2	K/W
	Sin.180° per thyristor			1.24	K/W
	ont.per W1C			0.6	K/W
	Sin.180° per W1C			0.62	K/W

PRODUCT SELECTOR					
PART NUMBER	VOLTAGE (xx)		SENSITIVITY	TYPE	PACKAGE
	1200V	1600V			
100KQxxK	V	V	80 mA	Snubberless	DBC module

ORDERING INFORMATION					
ORDERING TYPE	MARKING	PACKAGE	WEIGHT	BASE Q'TY	DELIVERY MODE
100KQxxK	100KQxxK	DBC module	% g	50	Box

Note: xx = voltage

ORDERING INFORMATION SCHEME

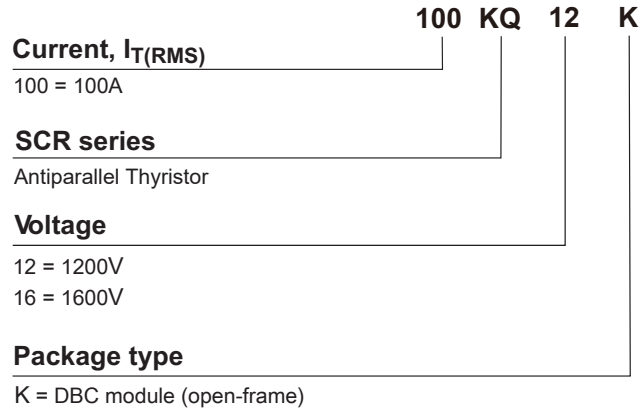


Fig.1 Maximum power dissipation versus on-state RMS current (full cycle)

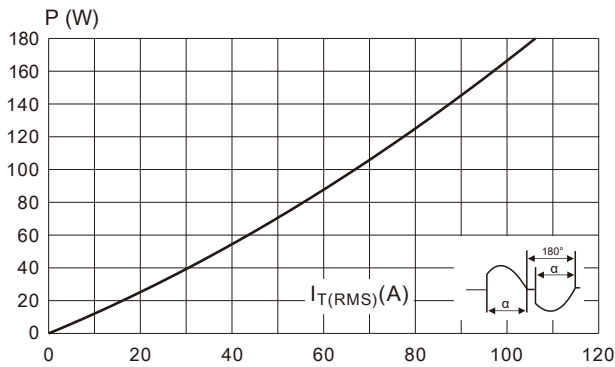


Fig.2 On-state rms current versus case temperature (full cycle)

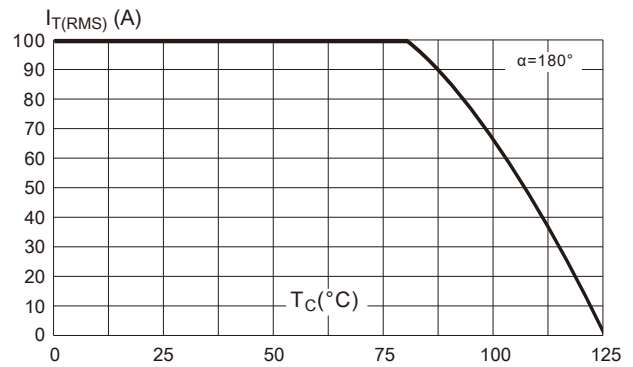


Fig.3 On-state characteristics (maximum values).

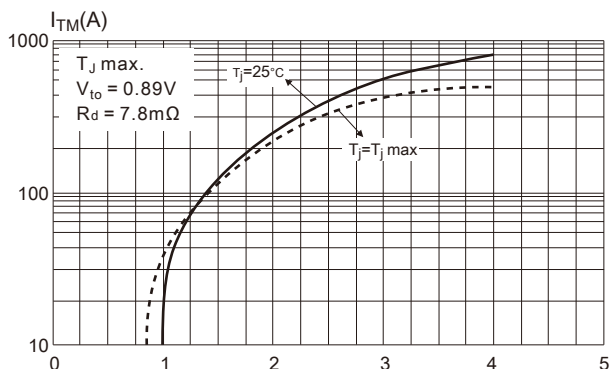


Fig.4 Surge peak on-state current versus number of cycles.

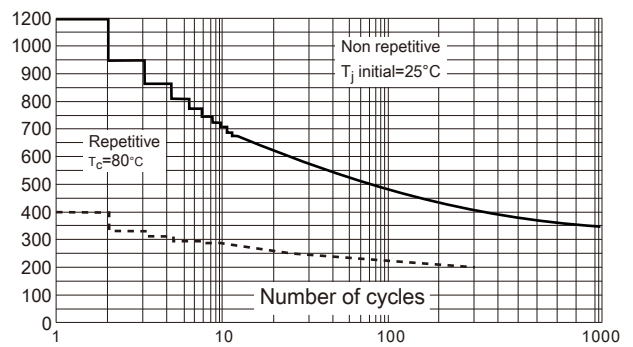


Fig.5 Non-repetitive surge peak on-state current for a sinusoidal pulse and corresponding value of I^2t .

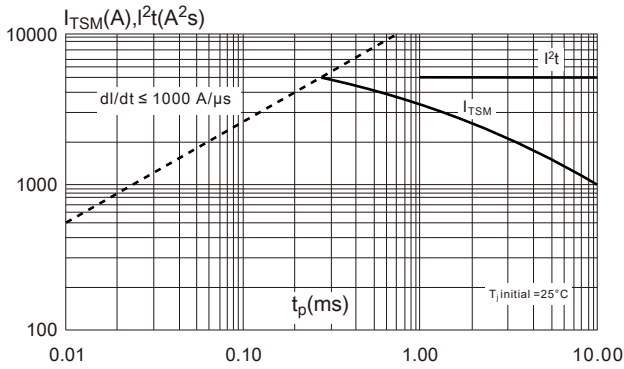
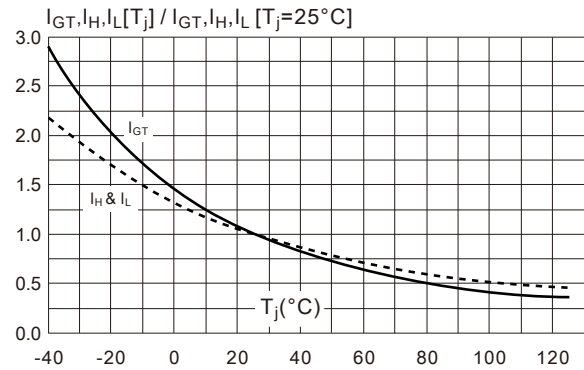
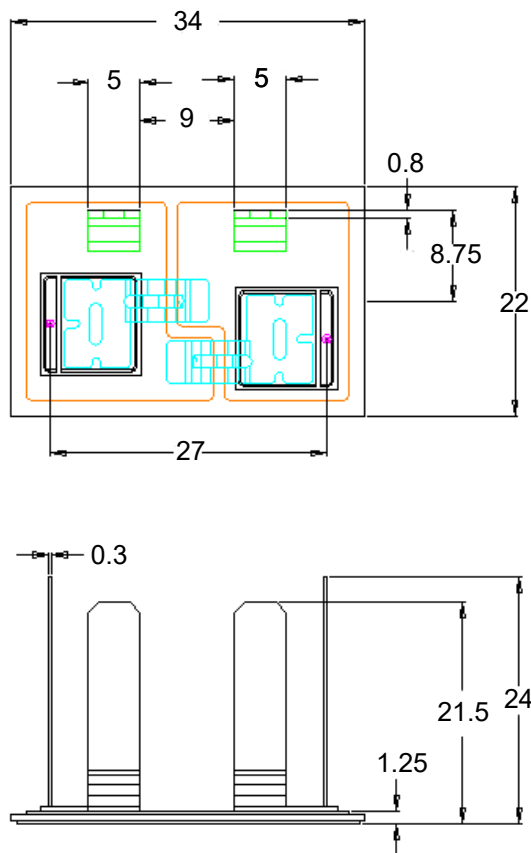


Fig.6 Relative variation of gate trigger, holding and latching current versus junction temperature (typical values)



Case Style



All dimensions in millimeters

